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Estimation of effective electron relaxation times in real thermoelectric materials¹ YUKARI KATSURA², The University of Tokyo, National Instutute of Materials Science, KAORU KIMURA, The University of Tokyo — Good samples of thermoelectric materials should be Phonon-Glass-Electron-Crystal (PGEC) [1], which scatters phonons without scattering electrons. However, the actual values of electron relaxation time τ_{el} are not well investigated, and τ_{el} is simply set as 10^{-14} s in many first-principles calculations of thermoelectric properties. In this study, we attempted to estimate the effective values of $\tau_{\rm el}$ of various thermoelectric materials, by fitting the calculation results by WIEN2k [2] and BoltzTraP [3] with experimental Seebeck coefficient and electrical conductivity. When we fitted experimental thermoelectric properties of Si_{0.8}Ge_{0.2} samples [4][5], $\tau_{\rm el}$'s at 300 K were 9×10^{-15} s in a highly crystalline sample [4], and 5-6 $\times 10^{-15}$ s in ball-milled polycrystalline samples [5]. Temperature dependences of $\tau_{\rm el}^{-1}$ were also different between samples, implying the difference in dominant electron scattering mechanisms. Various samples of thermoelectric materials with fairly high figures of merit exhibited $\tau_{\rm el}$ of several 10⁻¹⁵ s at 300 K. [1] G. A. Slack, CRC Handbook of Thermoelectrics, 407 (1995). [2] P. Blaha, et al., WIEN2k Users' Guide, Vienna Univ. of Technology, Austria (2001). [3] G.K.H. Madsen et al., Comp. Phys. Comm. 175, 67 (2006). [4] J.P. Dismukes et al., J. Appl. Phys. 10 2899 (1976). [5] C.B. Vining et al., J. Appl. Phys. 69 4333 (1991).

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